



Lead Free Package and Finish

**Applications:**

- DC-DC converter
- Portable Equipment
- Power management

$I_D$	$R_{DS(ON)}(Typ)$	$V_{DSS}$
174A	3.0mΩ	135V

**Features:**

- Low Reverse transfer capacitances
- Fast switching speed
- Low Gate Charge and  $R_{DS(on)}$

**Ordering Information**

Part Number	Package	Marking
RS135N170T	TO-220	RS135N170T



TO-220

Not to Scale

**Absolute Maximum Ratings  $T_c=25$  unless otherwise specified**

Symbol	Parameter	RS135N170T	Units
$V_{DSS}$	Drain-to-Source Voltage	135	V
$I_D$	Continuous Drain Current $T_C = 25\text{ }^\circ\text{C}$	174	A
	Continuous Drain Current $T_C = 100\text{ }^\circ\text{C}$	105	
$I_{DM}$	Pulsed Drain Current	640	
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
EAS	Single Pulse Avalanche Energy $L=0.5\text{mH } V_{DD}=70\text{V } R_G=25\Omega T_J=25$	1225	mJ
IAR	Single pulse avalanche current	70	A
PD	Total Power Dissipation @ $T_C=25$	250	W
TL TPKG	Maximum Temperature for Soldering	300	
	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds		
$T_J$ and $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to 150	

\* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.

**Thermal Resistance**

Symbol	Parameter	RS135N170T	Units	Test Conditions
$R_{\theta JC}$	Junction-to-Case	0.5	/ W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of +150
$R_{\theta JA}$	Junction-to-Ambient	60		1 cubic foot chamber, free air.

**OFF Characteristics**  $T_J=25^{\circ}\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV <sub>DSS</sub>	Drain-to-source Breakdown Voltage	135	--	--	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
I <sub>DSS</sub>	Drain-to-Source Leakage Current	--	--	1.0	μA	V <sub>DS</sub> =135V, V <sub>GS</sub> =0V
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	--	--	100	nA	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V
	Gate-to-Source Reverse Leakage	--	--	-100		V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V

**ON Characteristics**  $T_J=25^{\circ}\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance (Note*2)	--	3.0	3.6	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =20A
V <sub>GS(TH)</sub>	Gate Threshold Voltage	2.5	--	3.5	V	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250μA

**Resistive Switching Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
t <sub>d(ON)</sub>	Turn-on Delay Time	--	25	--	nS	V <sub>DS</sub> =70V I <sub>D</sub> =20A V <sub>GS</sub> =10V R <sub>G</sub> =5Ω
t <sub>rise</sub>	Rise Time	--	33	--		
t <sub>d(OFF)</sub>	Turn-OFF Delay Time	--	95	--		
t <sub>fall</sub>	Fall Time	--	75	--		

**Dynamic Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
C <sub>iss</sub>	Input Capacitance	--	8362	--	pF	V <sub>GS</sub> =0V V <sub>DS</sub> =70V f=1.0MHz
C <sub>oss</sub>	Output Capacitance	--	863	--		
C <sub>rss</sub>	Reverse Transfer Capacitance	--	14.2	--		
Q <sub>g</sub>	Total Gate Charge	--	138	--	nC	V <sub>DS</sub> =70V I <sub>D</sub> =20A V <sub>GS</sub> =10V
Q <sub>gs</sub>	Gate-to-Source Charge	--	34	--		
Q <sub>gd</sub>	Gate-to-Drain("Miller") Charge	--	32	--		

**Source-Drain Diode Characteristics**

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$I_S$	Continuous Source Current	--	--	174	A	Integral pn-diode in MOSFET
$I_{SM}$	Maximum Pulsed Current	--	--	640	A	
$V_{SD}$	Diode Forward Voltage	--	--	1.2	V	$I_S=20A, V_{GS}=0V$
$t_{rr}$	Reverse Recovery Time	--	130	--	nS	$V_{GS}=0V$ $I_S=20A, di/dt=100A/\mu s$
$Q_{rr}$	Reverse Recovery Charge	--	500	--	nC	

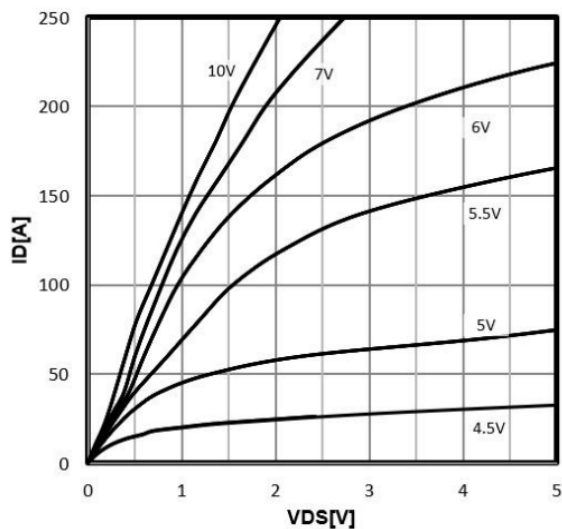
**Notes:**

\*1. Repetitive rating; pulse width limited by maximum junction temperature.

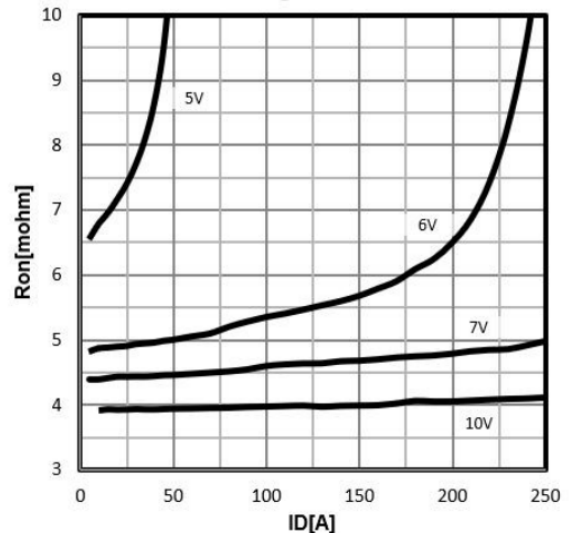
\*2. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty Cycle  $\leq 1\%$

**Typical Feature curve**

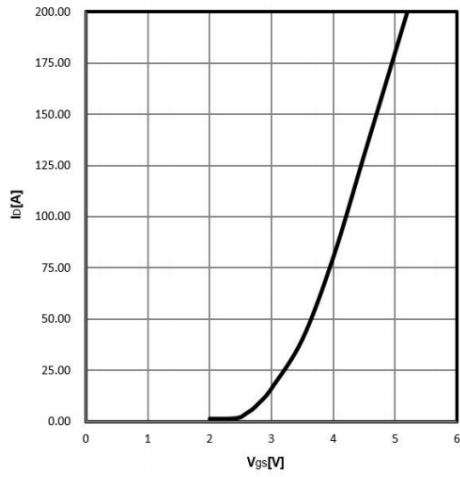
**Typ. output characteristics**  
 $I_D=f(V_{DS})$



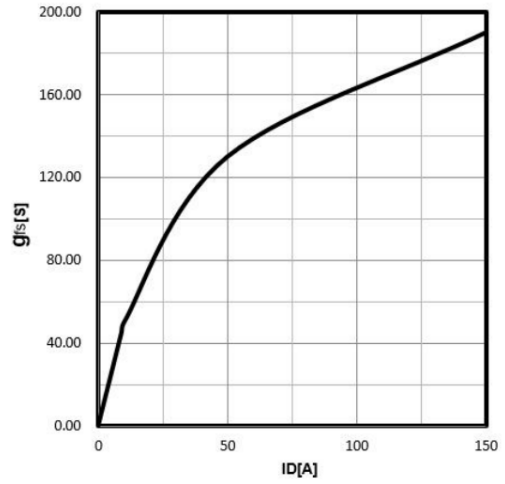
**Typ. drain-source on resistance**  
 $R_{DS(on)}=f(I_D)$



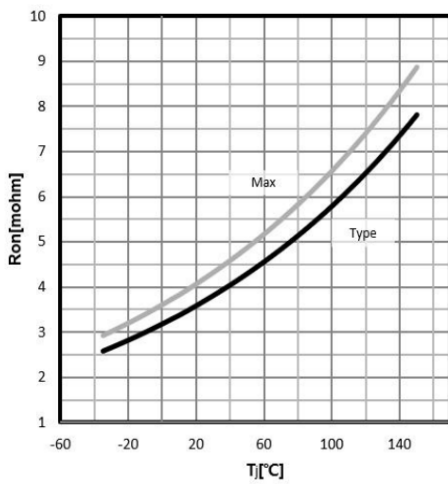
**Typ. transfer characteristics**  
 $I_D=f(V_{GS})$



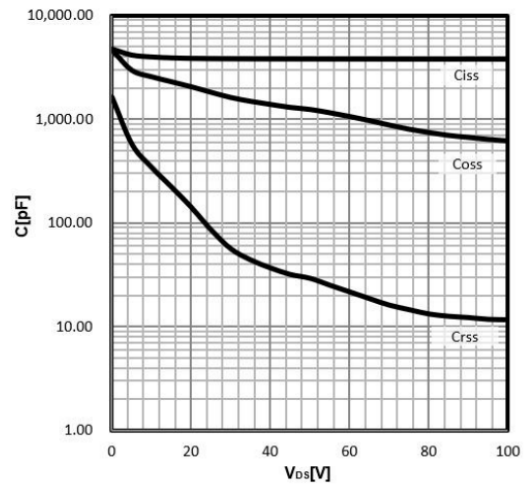
**Typ. forward transconductance**  
 $g_{fs}=f(I_D)$



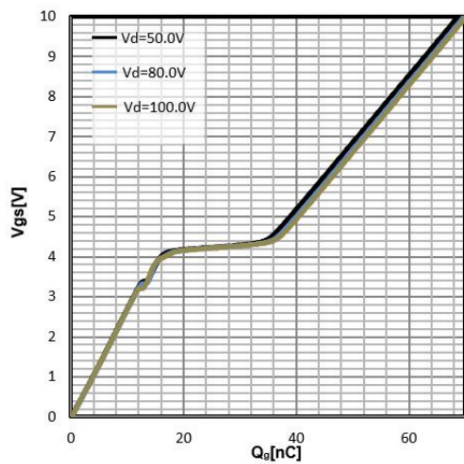
**Drain-source on-state resistance**  
 $R_{DS(on)}=f(T_J); I_D=80A; V_{GS}=10V$



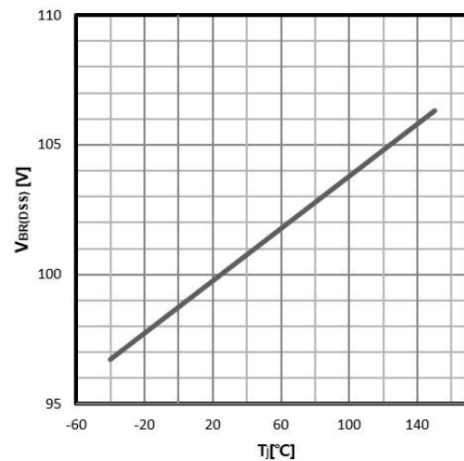
**Typ. capacitances**  
 $C=f(V_{DS}); V_{GS}=0V; f=1MHz$



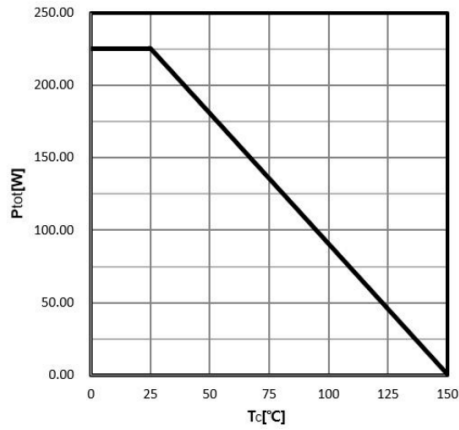
**Typ. gate charge**  
 $V_{GS}=f(Q_{gate}); I_D=20A$



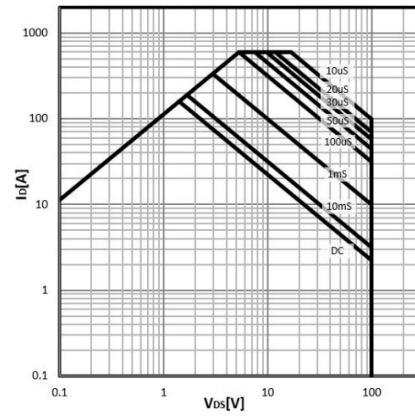
**Drain-source breakdown voltage**  
 $V_{BR(DSS)}=f(T_J); I_D=250uA$



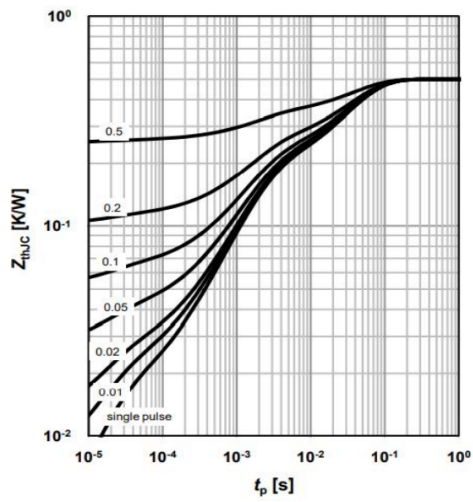
**Power Dissipation**  
 $P_{tot}=f(T_C)$



**Safe operating area**  
 $I_D=f(V_{DS})$



**Max. transient thermal impedance**  
 $Z_{thJC}=f(t_p)$



**Test Circuits and Waveforms**

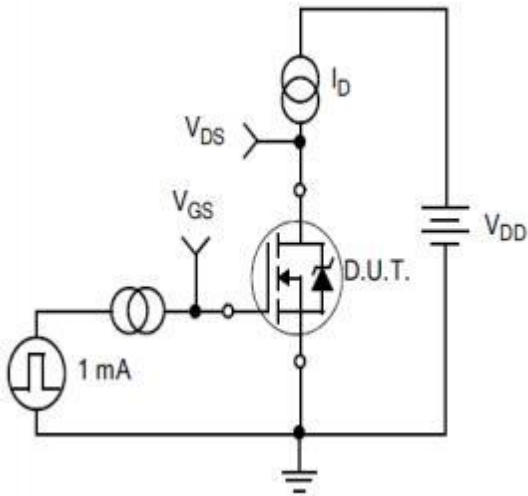


Figure A.  
Gate Charge Test Circuit

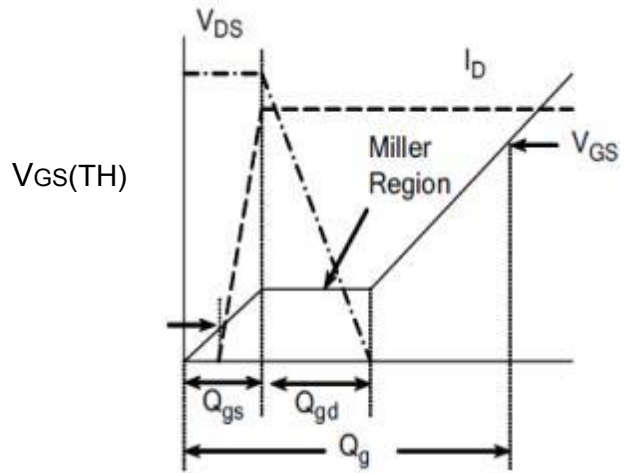


Figure B.  
Gate Charge Waveform

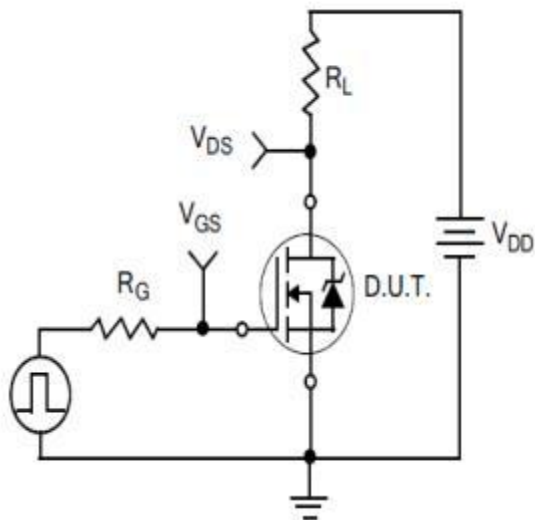


Figure C.  
Resistive Switching Test Circuit

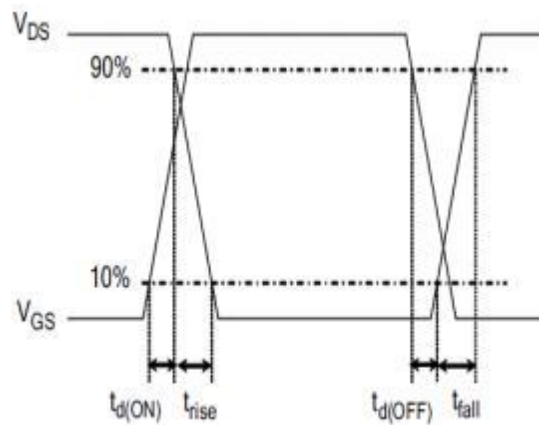


Figure D.  
Resistive Switching Waveforms

**Test Circuits and Waveforms**

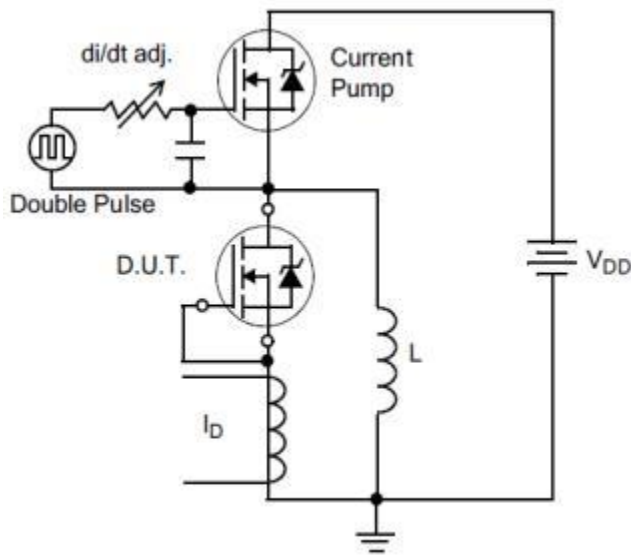


Figure E. Diode Reverse Recovery Test Circuit

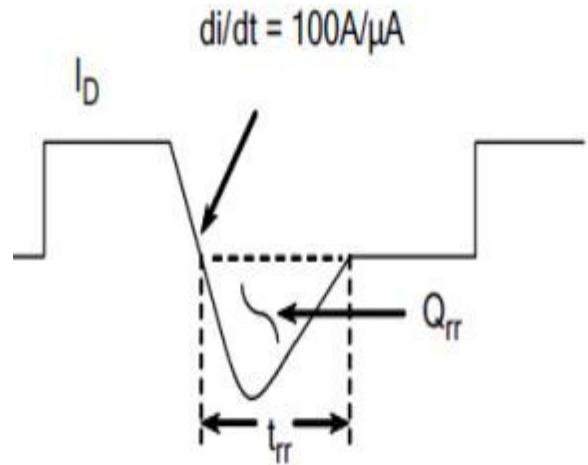


Figure F. Diode Reverse Recovery Waveform

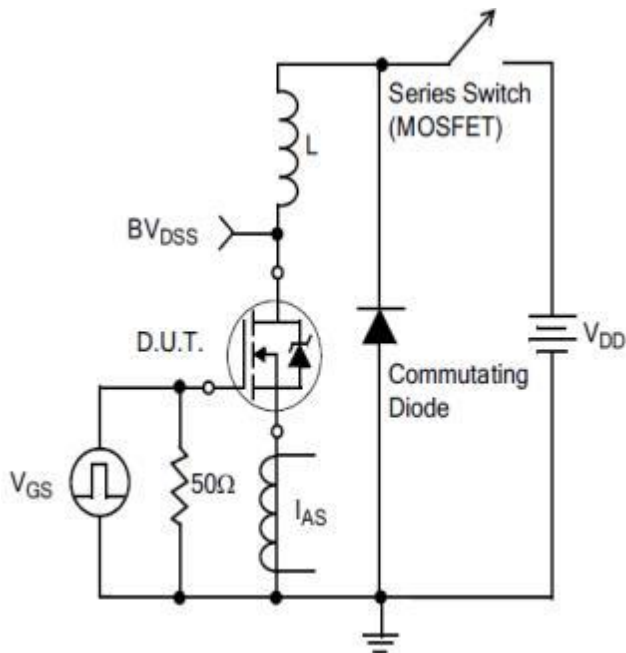
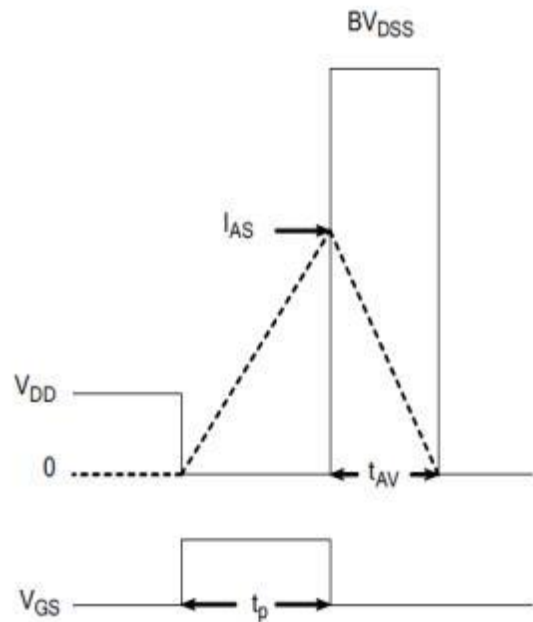


Figure G. Unclamped Inductive Switching Test Circuit



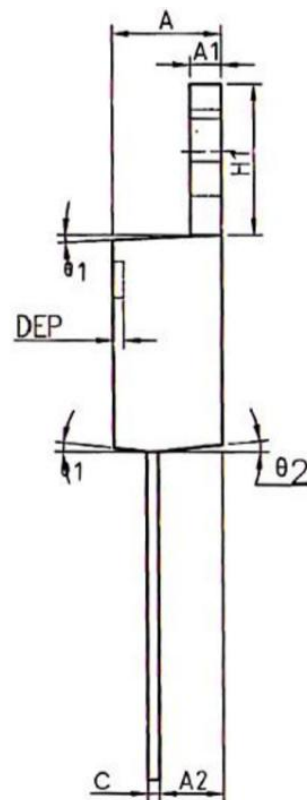
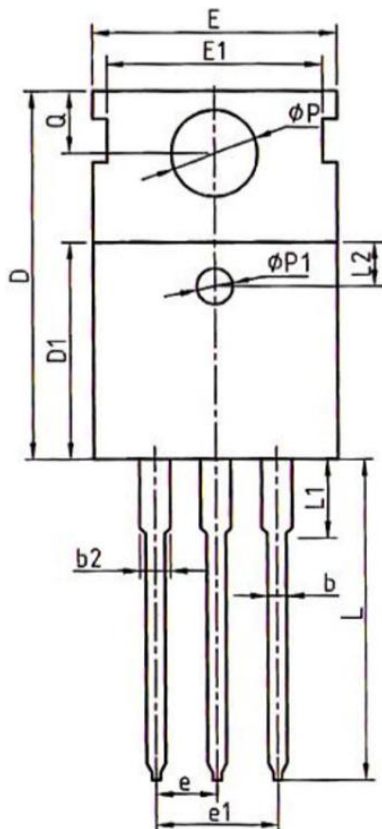
$$E_{AS} = \frac{I_{AS}^2 L}{2}$$

Figure H. Unclamped Inductive Switching Waveforms

Package outline drawing

TO-220

Unit:mm



COMMON DIMENSIONS

SYMBOL	MM		
	MIN	NDM	MAX
A	4.40	4.57	4.70
A1	1.27	1.30	1.37
A2	2.35	2.40	2.50
b	0.77	0.80	0.90
b2	1.17	1.27	1.36
c	0.48	0.50	0.56
D	15.40	15.60	15.80
D1	9.00	9.10	9.20
DEP	0.05	0.10	0.20
E	9.80	10.00	10.20
E1	-	8.70	-
E2	9.80	10.00	10.20
phi P1	1.40	1.50	1.60
e	2.54BSC		
e1	5.08BSC		
H1	6.40	6.50	6.60
L	12.75	13.50	13.65
L1	-	3.10	3.30
L2		2.50REF	
phi P	3.50	3.60	3.63
Q	2.73	2.80	2.87
theta 1	5°	7°	9°
theta 2	1°	3°	5°
theta 3	1°	3°	5°



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